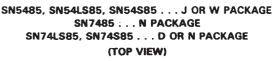
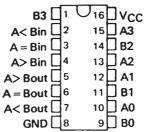
	TYPICAL	TYPICAL
TYPE	POWER	DELAY
	DISSIPATION	(4-BIT WORDS)
'85	275 mW	23 ns
<b>LS85</b>	52 mW	24 ns
<b>'</b> \$85	365 mW	11 ns

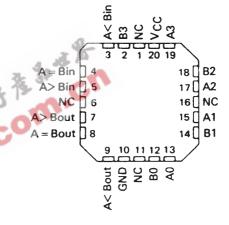
#### description

These four-bit magnitude comparators perform comparison of straight binary and straight BCD (8-4-2-1) codes. Three fully decoded decisions about two 4-bit words (A, B) are made and are externally available at three outputs. These devices are fully expandable to any number of bits without external gates. Words of greater length may be compared by connecting comparators in cascade. The A > B, A < B, and A = B outputs of a stage handling less-significant bits are connected to the corresponding A > B, A < B, and A = B inputs of the next stage handling more-significant bits. The stage handling the least-significant bits must have a high-level voltage applied to the A = B input. The cascading paths of the '85, 'LS85, and 'S85 are implemented with only a two-gate-level delay to reduce overall comparison times for long words. An alternate method of cascading which further reduces the comparison time is shown in the typical application data.





# SN54LS85, SN54S85 . . . FK PACKAGE (TOP VIEW)

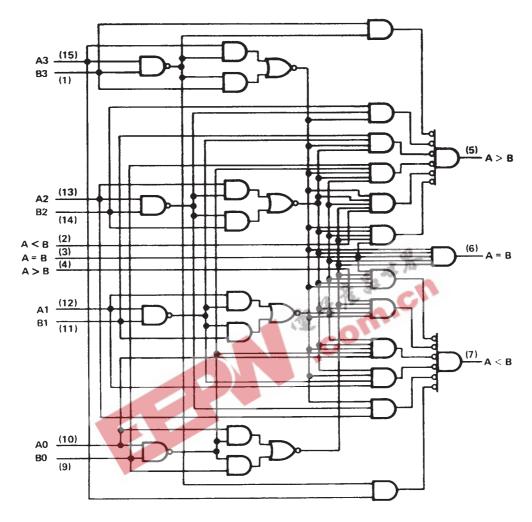


NC - No internal connection

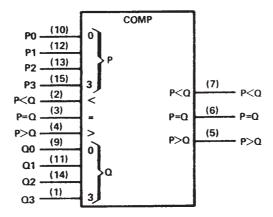
#### **FUNCTION TABLE**

		ARING UTS			CASCADING INPUTS		OUTPUTS			
A3, B3	A2, B2	A1, B1	A0, B0	A > B	A < B	A = B	A > B	A < B	A = 8	
A3 > B3	×	Х	×	Х	Х	Х	Н	L	L	
A3 < B3	×	×	×	х	X	Х	L	Н	L	
A3 = B3	A2 > B2	×	×	х	×	X	н	L	L	
A3 = B3	A2 < B2	×	×	х	X	Х	L	Н	L	
A3 = B2	A2 = B2	A1 > B1	×	х	×	X	Н	L	L	
A3 = B3	A2 = B2	A1 < B1	×	х	×	X	L	н	L	
A2 = B3	A2 = B2	A1 = B1	A0 > B0	×	×	X	Н	L	L	
A3 = B3	A2 = B2	A1 = B1	A0 < B0	x	x	X	L	Н	L	
A3 = B3	A2 = B2	A1 = B1	AO = BO	н	L	L	Н	L	L	
A3 = B3	A2 = B2	A1 = B1	AO = BO	L	H	L	L	н	L	
A3 = B3	A2 = B2	A1 = B1	AO = BO	x	×	Н	L	Ĺ	н	
A3 = B3	A2 = B2	A1 = B1	AO = BO	н	н	L	L	L	L	
A3 = B3	A2 = B2	A1 = B1	A0 = B0	L	L	L	н	Н	L	

### logic diagrams (positive logic)



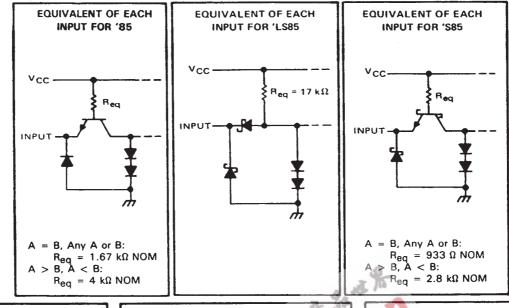
logic symbol†

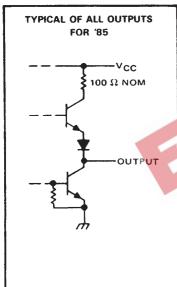


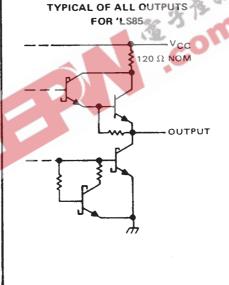
<sup>†</sup>This symbol is in accordancae with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for D, J, N, and W packages.

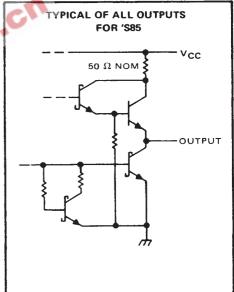


### schematics of inputs and outputs









## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

	SN54' SN54S'	SN54LS'	SN74' SN74S'	SN74LS'	UNIT
Supply voltage, V <sub>CC</sub> (see Note 1)	7	7	7	7	V
Input voltage	5.5	7	5.5	7	V
Interemitter voltage (see Note 2)	5.5		5.5		V
Operating free-air temperature range	- 55	to 125	-0	to 70	°C
Storage temperature range	-65	to 150	- 65	to 150	°C

NOTES: 1. Voltage values, except interemitter voltage, are with respect to network ground terminal.

2. This is the voltage between two emitters of a multiple-emitter input transistor. This rating applies to each A input in conjunction with its respective B input of the '85 and 'S85.



# SN5485, SN54LS85, SN54S85 SN7485, SN74LS85, SN74S85 **4-BIT MAGNITUDE COMPARATORS**

SDLS123 - MARCH 1974 - REVISED MARCH 1988

### recommended operating conditions

		SN5485	5		5		
	MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC</sub>	4.5	5	5.5	4.75	5	5.25	V
High-level output current, IOH			-400			-400	μА
Low-level output current, IOL			16			16	mA
Operating free-air temperature, TA	-55		125	0		70	°C

### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER		TEST	CONDITIONS	MIN	TYP‡ MAX	UNIT
ViH	High-level input voltage				2		V
VIL	Low-level input voltage					0.8	V
VIK	Input clamp voltage		V <sub>CC</sub> = MIN,	I <sub>I</sub> = -12 mA		-1.5	V
Vон	High-level output voltage		V <sub>CC</sub> = MIN, V <sub>IL</sub> = 0.8 V,	V <sub>IH</sub> = 2 V, I <sub>OH</sub> = -400 μA	2.4	3,4	V
VOL	Low-level output voltage		V <sub>CC</sub> = MIN, V <sub>IL</sub> = 0.8 V,	V <sub>IH</sub> = 2 V, 1 <sub>OL</sub> = 16 mA		0.2 0.4	V
11	Input current at maximum inp	ut voltage	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 5.5 V			mA
ЧН	High-level input current	A < B, A > B inputs all other inputs	V <sub>CC</sub> = MAX,	V <sub>I</sub> = 2.4 V		40 120	⊢ uA
1 <sub>1</sub> L	Low-level input current	A < B, A > B inputs all other inputs	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 0.4 V		-1.6 -4.8	-l mA
los	Short-circuit output current §		V <sub>CC</sub> = MAX, V <sub>C</sub>	SN5485 SN7485		59 59	⊢l mA
1cc	Supply current		V <sub>CC</sub> = MAX, Sec	e Note 4		55 88	mA

<sup>†</sup>For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

# switching characteristics, VCC = 5 V, TA = 25°C

PARAMETER	FROM INPUT	TO OUTPUT	NUMBER OF GATE LEVELS	TEST CONDITIONS	MIN T	YP I	MAX	UNIT
			1			7		
		A < B, $A > B$	2			12		]
<sup>t</sup> PLH	Any A or B data input		17	26	ns			
		A = B	4		:	23	35	
		A < B, A > B	1			1		
	Any A or B data input		2	C 15 -5		5		]
<sup>t</sup> PHL			3	$C_L = 15 pF$ , $R_L = 400 \Omega$ ,		20	30	ns
		A = B	4	See Note 5		20	30	
tPLH	A < B or A = B	A > B	1	See Note 5		7	11	ns
<sup>t</sup> PHL	A < B or A = B	A > B	1	1		11	17	ns
t <sub>PLH</sub>	A = 8	A = B	2			13	20	ns
<sup>t</sup> PHL	A = B	A = B	2	- -		l 1	17	ns
<sup>t</sup> PLH	A > B or A = B	A < B	1			7	11	ns
tPHL.	A > B or A = B	A < B	1	1		11	17	пѕ

TtpLH = propagation delay time, low-to-high-level output

NOTE 5: Load circuits and voltage waveforms are shown in Section 1.



<sup>‡</sup>All typical values are at  $V_{CC}$  = 5 V,  $T_A$  = 25° C. §Not more than one output should be shorted at a time.

NOTE 4:  $I_{CC}$  is measured with outputs open, A = B grounded, and all other inputs at 4.5 V.

tpHL = propagation delay time, high-to-low-level output

### recommended operating conditions

	S	N54LS	35	S	35		
	MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC</sub>	4.5	5	5.5	4.75	5	5.25	V
High-level output current, IOH			-400			-400	μА
Low-level output current, IQL			4			8	mA
Operating free-air temperature, TA	-55		125	0		70	°c

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

					S	N54LS8	15	S	N74LS8	5	
	PARAM	METER	TEST COM	IDITIONST	MIN	TYP‡	MAX	MIN	TYP <sup>‡</sup>	MAX	UNIT
VIH	High-level input	voltage			2			2			V
VIL							0.7			0.7	V
VIK	Input clamp volt	tage	VCC = MIN,	I <sub>I</sub> = -18 mA			-1.5			-1.5	٧
\/-··	High Involution	t voltage	V <sub>CC</sub> = MIN,	V <sub>1H</sub> = 2 V,	2.5	3.4		2.7	3.4		l v
vон	High-level outpu	t vortage	V <sub>I</sub> L = V <sub>I</sub> L max,	$I_{OH} = -400 \mu A$	2.5						
			V <sub>CC</sub> = MIN,	IOL = 4 mA		0.25	0.4		0.25	0.4	
$v_{OL}$	OL Low-level output voltage		V <sub>1H</sub> = 2 V,			a			0.35	0.5	\ \
			VIL = VIL max	1 <sub>OL</sub> = 8 mA	- 4	K-					<b>↓</b> _
	Input current	A < B, A > B inputs		V1 = 7 V 3	300	-	0.1			0.1	mA
11	at maximum input voltage	all other inputs	V <sub>CC</sub> = MAX,	VI = /V /3			0.3			0.3	] "'
	High-level	A < B, A > B inputs		V <sub>1</sub> = 2.7 V	170		20			20	μА
ΉН	input current	all other inputs	VCC = MAX,	VI = 2.7			60			60	] " "
	Low-level	A < B, A > B inputs	2	V =0.4.V			-0.4			-0.4	mA
HL	input current	all other inputs	V <sub>CC</sub> = MAX,	V <sub>1</sub> = 0.4 V			-1.2			-1.2	1
los	Short-circuit ou	tput current§	VCC = MAX		-20		-100	-20		-100	mA
¹cc	Supply current		V <sub>CC</sub> = MAX,	See Note 4		10.4	20		10.4	20	mA

NOTE 4: I<sub>CC</sub> is measured with outputs open, A = B grounded, and all other inputs at 4.5 V.

## switching characteristics, $V_{CC} = 5 \text{ V}$ , $T_A = 25^{\circ}\text{C}$

PARAMETER¶	FROM	то	NUMBER OF	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
PARAMETER :	INPUT	OUTPUT	GATE LEVELS					1	
	Any A or B data input			1			14		1
		A < B, A > B	2			19		ns	
tPLH			3			24	36		
		A = B	4	1		27	45		
		A < B, A > B		1	7		11		
			2	0 15-5		15		ns	
<sup>t</sup> PHL	Any A or B data input		3	$C_L = 15  pF$ ,		20	30		
		A = B	4	$R_L = 2 k\Omega$		23	45		
tPLH	A < B or A = B	A > B	1	See Note 5		14	22	ns	
tPHL	A < B or A = B	A > B	1			11	17	ns	
†PLH	A = B	A = B	2			13	20	ns	
tPHL	A = B	A = B	2			13	26	ns	
tPLH	A > B or A = B	A < B	1			14	22	ns	
tPHL	A > B or A = B	A < B	1			11	17	ns	

 $<sup>\</sup>P_{tPLH}$  = propagation delay time, low-to-high-level output

NOTE 5: Load circuits and voltage waveforms are shown in Section 1.



<sup>†</sup>For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. ‡All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25 ^{\circ}\text{C}$ . § Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.

tpHL = propagation delay time, high-to-low-level output

# SN5485, SN54LS85, SN54S85 SN7485, SN74LS85, SN74S85 4-BIT MAGNITUDE COMPARATORS

SDLS123 - MARCH 1974 - REVISED MARCH 1988

#### recommended operating conditions

		SN54S8	5	SN74S85			UNIT
	MIN	MOM	MAX	MIN	NOM	MAX	UNII
Supply voltage, V <sub>CC</sub>	4.5	5	5.5	4.75	5	5.25	V
High-level output current, IOH			-1			-1	mA
Low-level output current, IOL			20			20	mA
Operating free-air temperature, TA	-55		125	0		70	°C

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER		TEST CONDITIONS†		MIN	TYP‡	MAX	UNIT
VIH	High-level input voltage				2			V
VIL	Low-level input voltage						8.0	V
VIK	Input clamp voltage		VCC = MIN, II = -18 mA				-1.2	V
			V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2 V, S	N54S85	2.5	3.4		V
Voн	High-level output voltage		V <sub>IL</sub> = 0.8 V, I <sub>OH</sub> = -1 mA S	N74S85	2.7	3.4		
			V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2 V,				0.5	V
VOL	Low-level output voltage		VIL = 0.8 V, IOL = 20 mA				0.5	•
11	Input current at maximum input	t voltage	VCC = MAX, V1 = 5.5 V	-			1	mA
		A < B, A > B inputs	$V_{CC} = MAX, V_1 = 2.7 V$	5.0			50	μА
чн	High-level input current	all other inputs	VCC - WAX, VI - 2.7	-10			150	1
		A < B, A > B inputs	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.5 V	3 4			-2	mA
111	Low-level input current	all other inputs	1732				-6	11112
Ios	Short-circuit output current§		V <sub>CC</sub> = MAX		-40		-100	mA
			V <sub>CC</sub> = MAX, See Note 4			73	115	
¹cc	Supply current		V <sub>CC</sub> = MAX, T <sub>A</sub> = 125°C, See Note 4	N54S85W			110	mA

<sup>&</sup>lt;sup>†</sup>For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

### switching characteristics, VCC = 5 V, TA = 25°C

PARAMETER¶	FROM INPUT	TO OUTPUT	NUMBER OF GATE LEVELS	TEST CONDITIONS	MIN TYP	MAX	UNIT	
			1		5		}	
		A < B, A > B	2		7.5		ns	
<sup>t</sup> PLH	Any A or B data input		3		10.5	16	] ""	
		A = B	4		12	18		
		A < B, A > B	1	1	5.5			
	Any A or B data input		A < B, A > B	2	0 - 45 - 5	7		ns
<sup>t</sup> PHL			3	C <sub>L</sub> = 15 pF,	11	16.5	1	
		A = B	4	R <sub>L</sub> = 280 Ω, See Note 5	11	16.5		
tPLH	A < B or A = B	A > B	1	See Note 5	5	7.5	ns	
tPHL.	A < B or A = B	A > B	1	1	5.5	8.5	ns	
tPLH	A = B	A = B	2		7	10.5	ns	
tPHL	A = B	A = 8	2	1	5	7.5	ns	
tPLH	A > B or A = B	A < B	1	1	5	7.5	ns	
tPHL	A > B or A = B	A < B	1		5.5	8.5	ns	

<sup>¶</sup>tpLH = propagation delay time, low-to-high-level output

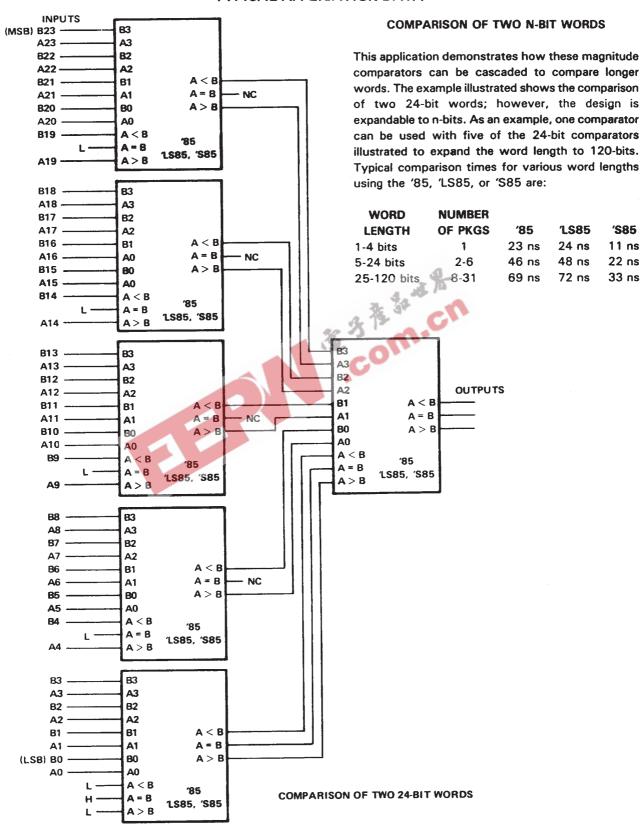
NOTE 5: Load circuits and voltage waveforms are shown in Section 1.



<sup>‡</sup>All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25° C. §Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second. NOTE 4: I<sub>CC</sub> is measured with outputs open, A = B grounded, and all other inputs at 4.5 V.

tpHL = propagation delay time, high-to-low-level output

#### TYPICAL APPLICATION DATA



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